

INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>	Docket Number (Optional) NSC1-M3300 [P05678]		Application Number New
	Applicant(s) Charles Dark et al..		
	Filing Date Herewith		Group Art Unit Unknown

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE

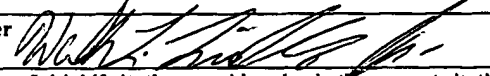
FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

OTHER DOCUMENTS

(Including Author, Title, Date, Pertinent Pages, Etc.)

WL	A	"The Effects of Fluorine on Parametrics and Reliability in a 0.18- μ m 3.5/6.8 nm Dual Gate Oxide CMOS Technology";					
WL		Terence B. Hook et al.; IEEE Transactions on Electron Devices, Vol. 48, No. 7, July 2001; pp 1346-1353					

Examiner 	Date Considered 6/23/04
Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	